

10681116\_CLS  
Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10681116 on March 17, 2004

Original Classifications

3 348/351  
2 257/797  
2 313/413  
2 324/751  
2 347/55

Cross-Reference Classifications

5 348/356  
2 250/201.7  
2 257/620  
2 313/414  
2 348/355  
2 361/225  
2 396/89

Combined Classifications

5 348/356  
3 348/351  
2 250/201.7  
2 250/396R  
2 250/492.2  
2 257/620  
2 257/797  
2 313/413  
2 313/414  
2 324/751  
2 347/55  
2 348/354  
2 348/355  
2 361/225  
2 396/89  
2 716/4

10681116\_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 10681116 on March 17, 2004

5 348/356 (0 OR, 5 XR)  
 Class 348 : TELEVISION  
 348/207.99 CAMERA, SYSTEM AND DETAIL  
 348/335 .Optics  
 348/345 ..Focus control  
 348/349 ...Using image signal  
 348/354 ....By analyzing high frequency component  
 348/356 .....Detection of peak or slope of image signal

1

3 348/351 (3 OR, 0 XR)  
 Class 348 : TELEVISION  
 348/207.99 CAMERA, SYSTEM AND DETAIL  
 348/335 .Optics  
 348/345 ..Focus control  
 348/349 ...Using image signal  
 348/351 ....With oscillation of lens or sensor to  
 optimize error signal

2 250/201.7 (0 OR, 2 XR)  
 Class 250 : RADIANT ENERGY  
 250/200 PHOTOCELLS; CIRCUITS AND APPARATUS  
 250/201.1 .Photocell controls its own optical systems  
 250/201.2 ..Automatic focus control  
 250/201.7 ...Based on contrast

2 250/396R (1 OR, 1 XR)  
 Class 250 : RADIANT ENERGY  
 250/396R WITH CHARGED PARTICLE BEAM DEFLECTION OR  
 FOCUSING

2 250/492.2 (1 OR, 1 XR)  
 Class 250 : RADIANT ENERGY  
 250/492.1 IRRADIATION OF OBJECTS OR MATERIAL  
 250/492.2 .Irradiation of semiconductor devices

2 257/620 (0 OR, 2 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/618 PHYSICAL CONFIGURATION OF SEMICONDUCTOR (E.G.,  
 MESA, BEVEL, GROOVE, ETC.)  
 257/620 .With peripheral feature due to separation of  
 smaller semiconductor chip from larger wafer

10681116\_CLSTITLES

r (e.g., scribe

ch as leakage

region, or means to prevent edge effects su

current at peripheral chip separation area)

2 257/797 (2 OR, 0 XR)

Class 257 : ACTIVE SOLID-STATE DEVICES  
257/797 ALIGNMENT MARKS

2 313/413 (2 OR, 0 XR)

Class 313 : ELECTRIC LAMP AND DISCHARGE DEVICES  
313/364 CATHODE RAY TUBE  
313/409 .Plural beam generating or control  
313/413 ..With deflection

2 313/414 (0 OR, 2 XR)

Class 313 : ELECTRIC LAMP AND DISCHARGE DEVICES  
313/364 CATHODE RAY TUBE  
313/409 .Plural beam generating or control  
313/414 ..With focusing and accelerating electrodes

2 324/751 (2 OR, 0 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .Of individual circuit component or element  
324/750 ..System sensing fields adjacent device under  
test (DUT)  
324/751 ...Using electron beam probe

2 347/55 (2 OR, 0 XR)

Class 347 : INCREMENTAL PRINTING OF SYMBOLIC INFORMATION  
347/1 INK JET  
347/20 .Ejector mechanism (i.e., print head)  
347/54 ..Drop-on-demand  
347/55 ...With electric field ejection (applied to  
fluid)

2 348/354 (1 OR, 1 XR)

Class 348 : TELEVISION  
348/207.99 CAMERA, SYSTEM AND DETAIL  
348/335 .Optics  
348/345 ..Focus control  
348/349 ...Using image signal  
348/354 ....By analyzing high frequency component

10681116\_CLSTITLES

2 348/355 (0 OR, 2 XR)  
     Class 348 : TELEVISION  
     348/207.99 CAMERA, SYSTEM AND DETAIL  
     348/335 .Optics  
     348/345 ..Focus control  
     348/349 ...Using image signal  
     348/354 ....By analyzing high frequency component  
     348/355 .....Plural high frequencies

2 361/225 (0 OR, 2 XR)  
     Class 361 : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES  
     361/225 ELECTRIC CHARGING OF OBJECTS OR MATERIALS

2 396/89 (0 OR, 2 XR)  
     Class 396 : PHOTOGRAPHY  
     396/89 WITH EXPOSURE OBJECTIVE FOCUSING MEANS,  
             FOCUSING AID, OR RANGEFINDING MEANS

2 716/4 (1 OR, 1 XR)  
     Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
                 CIRCUIT OR SEMICONDUCTOR MASK  
     716/1 CIRCUIT DESIGN  
     716/4 .Testing or evaluating